A Tandem Parallel Plate Analyzer

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ABSTRACT. By a new modification of a parallel plate analyzer the second-order focus is obtained in an arbitrary injection angle. This kind of an analyzer with a small injection angle will have an advantage of small operational voltage, compared to the Proca and Green analyzer where the injection angle is 30 degrees. Thus, the newly proposed analyzer will be very useful for the precise energy measurement of high energy particles in MeV range.

Keywords: analyzer, parallel plate analyzer, beam, HIBP
1. INTRODUCTION

The parallel plate electrostatic energy analyzer\textsuperscript{1,2} is widely used in various fields of experimental physics and technology because of its simplicity and good focusing properties up to the second order in case of 30 degrees injection angle. It is also suited for the simultaneous multi-input-slit measurement of the energy of nearly parallel beams, since we can install many input-slit/detector sets utilizing the fact that the electric field is uniform.

In order to perform high-precision measurement of the energy of particles in MeV range by a parallel plate analyzer, the second-order focus is necessary and the injection angle must be 30 degrees. Then we have to apply a very high voltage of $V_a > (V_t \sin^2(\theta_{in})) / q_s$ to the upper parallel plate in order to bend the trajectory, where $V_t$ is the energy of the particle and $\theta_{in}$ is the injection angle. $q_s$ is the charge of the particle. In order to reduce the operational voltage, the injection angle must be reduced at the sacrifice of the second-order focus.

Here, we would like to propose a tandem parallel plate analyzer which has the second-order focus at any injection angle. By this analyzer, the multi-slit measurement of the precise change of the energy of several nearly parallel beams in MeV range may be more easily performed.

A heavy ion beam probe for the large plasma confinement machine, utilizes several MeV heavy ion beam and is required to measure the change of a few hundreds eV in the energy of the beam out of the plasma\textsuperscript{3,4}. Since heavy ions like gold or thallium are used, a sector magnet for energy analysis may be larger than the
confinement machine itself and very expensive. In addition, the multi-input-slit measurement by a sector magnet or electrostatic cylindrical deflector, to determine the wavelength of the turbulence in a plasma is very limited. This analyzer may be very useful to this kind of application.

2. ANALYZER MODEL AND THEORY

First, we discuss the aberration of a single parallel plate analyzer as shown in Fig. 1(a). The basic equation of the trajectory (x, y) in the field free region after deflection by the uniform electric field is given by,

\[ x = (h+y)\cot(\theta) + \frac{2.0V_t}{q_sE_p} \sin(2\theta), \]  

(1)

where, \((0, h)\) is position of the entrance slit of the analyzer as shown in Fig. 1(a). \(V_t\) is the energy of the particle and \(E_p\) is the electric field at the analyzer. The charge of the particle is \(q_s\). \(\theta\) is the injection angle to the analyzer.

The aberration \(\delta x\) of a parallel plate analyzer at the focal point due to the change of the entrance angle to the analyzer \(\delta \theta\) is described by the following equation:\(^2\),

\[ \delta x = \frac{4V_t \cos(3\theta_1)(\delta \theta)^2 - 4V_t \cos(2\theta_1)(\delta \theta)^3}{q_sE_p \sin(\theta_1) \sin^2(\theta_1)}. \]

(2)

where \(\theta = \theta_1 + \delta \theta\) and \(\theta_1\) is the injection angle of the first-order focus. At \(\theta_1 = 30^\circ\), the second-order focus is obtained.

We discuss a model of a tandem parallel plate analyzer as shown in Fig. 1(b). The angle of a base plate \((\theta_s)\) is given by \(\theta_s = \theta_1 + \theta_2\), where \(\theta_1, \theta_2\) are the designed entrance angles to the first and second
stages of a tandem analyzer respectively. The aberration of a tandem parallel plate analyzer can be calculated by the following equation of the straight trajectory after deflection by the second deflector,

$$\delta x_1 = \left\{ L_x - h_1 \cot(\theta) \right\} \frac{q_v}{q_4 E_{p1}} \frac{2.0V_s \sin(2\theta)}{\sin(\theta_a)} + \frac{2.0V_s \sin(2\theta a) + h_2 \cot(\theta a)}{q_4 E_{p2}}, \quad (3)$$

where $\theta_a = \theta_g - \theta$. Other parameters are shown in Fig. 1(b). By a simple calculation, it is shown the terms of $L_x \frac{\sin(\theta)}{\sin(\theta_a)}$ and $h_1 \cot(\theta) \frac{\sin(\theta)}{\sin(\theta_a)}$ are a linear function of $h_2 \cot(\theta a)$. Accordingly, we have three independent parameters of $E_{p1}$, $E_{p2}$ and $h_2$, and we can find second-order focus at arbitrary angles of $\theta_1$, $\theta_2$ by the equations of $\frac{\delta x_1}{\delta \theta} = 0$ and $\frac{\delta^2 x_1}{\delta \theta^2} = 0$. The ratio of the electric fields under the parallel plates is given by the following equation after somewhat lengthy calculation,

$$\frac{\cos(3\theta_1)}{E_{p1}} = \frac{\cos(3\theta_2)}{E_{p2}}. \quad (4)$$

The final aberration can be expressed in the following equation,

$$\delta x_1 = 4V_s \frac{\cos(2\theta_1) \sin(\theta) \cos(3\theta_2) - \cos(3\theta_1) \cos(3\theta_2) \sin(\theta_1 + \theta_2) + \cos(3\theta_1) \sin(\theta_1) \cos(2\theta_2)}{q_4 E_{p1} \sin(\theta_1) \sin^2(\theta_2)} (\delta \theta)^3. \quad (5)$$

We can derive Eqs. (4) and (5) readily in the following way. We can assume without loss of generality that $g(\theta_1) = 0$, $\frac{\delta g(\theta)}{\delta \theta} = 0$, at $\theta = \theta_1$, where $g(\theta) = L_x - h_1 \cot(\theta) - \frac{2.0V_s \sin(2\theta)}{q_4 E_{p1}}$, since $L_x \frac{\sin(\theta)}{\sin(\theta_a)}$ and $h_1 \cot(\theta) \frac{\sin(\theta)}{\sin(\theta_a)}$ are a linear function of $h_2 \cot(\theta a)$. Then in the
calculation of \( \frac{\delta x_1}{\delta \theta} = 0 \) and \( \frac{\delta^2 x_1}{\delta \theta^2} = 0 \) at \( \Pi_2 \), we can use Eq. (2) and more easily Equations (4) and (5) are obtained.

The focus point \((x_{If}, h_{If})\) is given by,

\[
x_{If} = \frac{4V_i}{q_sE_p2} \sin(2\theta_2) \cos^2(\theta_2) \left[ L_t - \frac{4V_i}{q_sE_p1} \sin(2\theta_1) \cos^2(\theta_1) \right] \cos(\theta_s) - \left[ h_1 - \frac{4V_i}{q_sE_p1} \cos(2\theta_1) \sin^2(\theta_1) \right] \sin(\theta_s)
\]

(6)

\[
h_{If} = \frac{4V_i}{q_sE_p2} \cos(2\theta_2) \sin^2(\theta_2) - L_s \sin(\theta_s) + h_1 \cos(\theta_s)
\]

(7)

Figure 2(a) shows the angular aberration of the tandem parallel plate analyzer, \( x_1(\theta) \) versus \( \theta \) when \( \theta_1 = 9^\circ, \theta_2 = 13^\circ, \frac{V_t}{(q_sE_p1)} = 1 \) and Equation (4) is satisfied. The dashed curve shows the approximate curve utilizing Eq. (5). In Fig. 1(b) the calculated trajectories of the particle in the analyzer are shown when the incident angle is changed from 7° to 10° under the same parameters. In contrast to Fig. 2(a), the angular aberration of a usual parallel plate analyzer with \( \theta_1 = 9^\circ \) injection angle is shown in Fig. 2(b). It is clearly shown that the improvement in the aberration by a factor of several tens is obtained by the tandem analyzer by comparing Fig. 2(a) and 2(b). Figure 2(c) shows the energy dispersion of the tandem parallel plate analyzer (\( \frac{\delta x_{If}}{\delta V_i} \)) and the energy dispersions of the second stage of the analyzer under the assumption that the energy is changed only at the second stage. The dispersion is somewhat reduced due to the negative contribution at the first stage of the analyzer.

In conclusion, it is shown that a parallel plate analyzer has the second-order focus at arbitrary injection angle by a simple
modification. This analyzer may be useful for the precise measurement of particles in MeV range, since the upper plate voltage can be enough low for high voltage breakdown by adopting low injection angle to the analyzer.

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Reference


Figure Captions

Figure 1(a). Schematics of a parallel plate analyzer. 1(b).
Schematic view of a tandem parallel analyzer. The trajectories of the particle are calculated and shown at the second-order focus condition. \( \theta_1 = 9^\circ, \theta_2 = 13^\circ \). \( V_t/(q_B E_p) = 1 \) and Equation (4) is satisfied. The incident angle is changed from 7\(^\circ\) to 10\(^\circ\) by 1\(^\circ\).

Figure 2. Characteristics of the tandem parallel plate analyzer.
2(a). The angular aberration of the tandem parallel plate analyzer, \( x_1(\theta) \) versus \( \theta \) when \( \theta_1 = 9^\circ, \theta_2 = 13^\circ \). \( V_t/(q_B E_p) = 1 \). Equation (4) is satisfied. \( x_1 \) is the distance from the corner to the focus point, as is shown in Fig. 1(b). Equation (3) is calculated near the second-order focal point. The dashed curve shows the approximate curve utilizing Eq. (5). 2(b). The angular aberration of a usual parallel-plate analyzer with the injection angle of 9\(^\circ\). Equation (1) is calculated near the focal point. \( V_t/(q_B E_p) = 1 \) is assumed. 2(c) shows the energy dispersion of the parallel plate analyzer. The
dashed curve shows the dispersion due to the second-stage of the analyzer.
Fig. 1(b)
Figure 2
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